

A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs

Cardoso Medeiros, Guilherme; **Gürsoy, Cemil Cem**; Fieback, Moritz; Wu, Lizhou; **Jenihhin, Maksim**; Taouil, Mottaqiallah; Hamdioui, Said 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / p. 792-797 <https://doi.org/10.23919/DATE48585.2020.9116278>

LiD-CAT: A lightweight detector for cache ATtacks

Reinbrecht, Cezar; Hamdioui, Said; Taouil, Mottaqiallah; **Niazmand, Behrad**; **Ghasempouri, Tara**; **Raik, Jaan**; Sepulveda, Johanna 2020 IEEE European Test Symposium (ETS) : ETS 2020, May 25-29, 2020 Tallinn, Estonia : proceedings 2020 / 6 p. : ill <https://doi.org/10.1109/ETS48528.2020.9131603>

On BTI aging rejuvenation in memory address decoders

Gürsoy, Cemil Cem; Kraak, Daniel; **Ahmed, Faisal**; Taouil, Mottaqiallah; **Jenihhin, Maksim**; Hamdioui, Said 2022 IEEE 23rd Latin American Test Symposium, LATS 2022 2022 / Code 184360 <https://doi.org/10.1109/LATS57337.2022.9936940>

Verifying cache architecture vulnerabilities using a formal security verification flow

Ghasempouri, Tara; **Raik, Jaan**; **Paul, Kolin**; Reinbrecht, Cezar; Hamdioui, Said; Taouil, Mottaqiallah Microelectronics reliability 2021 / art. 114085 <https://doi.org/10.1016/j.microrel.2021.114085> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)